IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In	Re	the	Ap	plica	ation	of:
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OFER ADAN, ET AL.

Application No.:

Filed:

For:

A Method for Measuring and Reducing **Angular Deviations of a Charged Particle**

Beam

Art Group:

Examiner:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In accordance with the duty of disclosure, enclosed is a copy of IDS Citation Form PTO/SB/08 or PTO-1449, together with copies of the documents cited on that form, except for copies not required to be submitted (e.g., copies of U.S. patents and U.S. published patent applications need not be enclosed). This IDS and IDS Citation Form are being submitted concurrently with the US National Stage Application base off PCT. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLF

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I hereby certify that this correspondence is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Iennifer L. Stewart

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JC20 Rec'd PCT/PTO 01 AUG 2005

INFOI STAT	for form 1449A/PTO RMATION D EMENT BY (use as many sheets	OISCLO APPL	ICANT	Application Number 1 1 2 2 Filing Date First Named Inventor
Sheet	1	of	2	Attorney Docket Number 6317P028

			U.S. PATE	NT DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number - Kind Code ² (if known)	Publication Date or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-6,472,662 B1	10-29-2002	Archie	
		US-6,025,600 A	02-15-2000	Archie et al.	
		US-6,028,662 A	02-22-2000	Sturans et al.	
		US-			
		US-		1.1	
		US-			

	FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite	Foreign Patent Document			Pages, Columns, Lines,			
	No.1	Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear			
		WO 01/45136 A	06-21-2001	Adamec Pavel, et al.				
		EP 1 150 327 A	10-31-2001	Integrated Circuit Testing				
	l							

Examiner	Dat	te
Signature	Con	nsidered

^{*}Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

^{&#}x27;Applicant's unique citation designation number (optional). 'See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. 'Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 'For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. 'Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. 'Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449A/PTO			<u> </u>		Complete if Known		
			CUPE	Application Number	10/5/1/122		
INFORMATION DISCLOSURE				Filing Date	IU/ Janzee		
STATEMENT BY APPLICANT				First Named Inventor	Ofer Adan		
				Art Unit			
				Examiner Name			
Sheet	2	of	2	Attorney Docket Number	6317P028		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.¹	symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		FUJITSU Ltd., Scanning Type Electron Microscope, Patent Abstracts of Japan, Vol. 18, No. 458, 1pg					
		SOLECKY E. ET AL, Three Dimensional Top Down Metrology: A Viable Alternative to AFM of Cross Section, Proceedings of SPIE, Vol. 4344 (2001), 8pp					
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Examiner		Date	$\overline{}$				

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^{&#}x27;Applicant's unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.